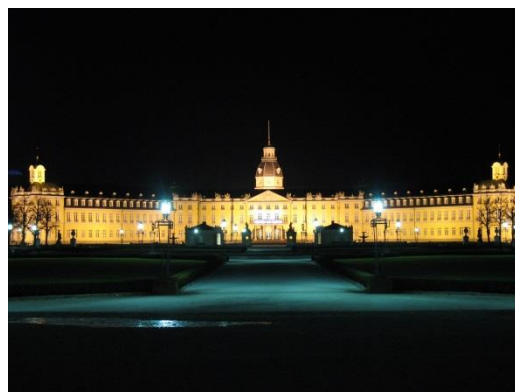


Vás zve na seminář:

AFM meeting in Karlsruhe

Zbyněk Heger, Jan Zítka, René Kizek



What is AFM?

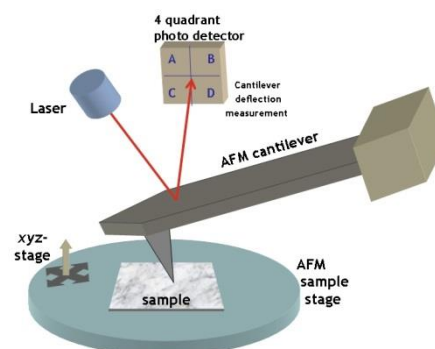
The atomic force microscope (AFM) is one kind of scanning probe microscopes (SPM). SPMs are designed to measure local properties, such as height, friction, magnetism, with a probe. To acquire an image, the SPM raster-scans the probe over a small area of the sample, measuring the local property simultaneously.

How does AFM work?



AFM meeting in Karlsruhe (18. 8 – 21. 8. 2014)

AFMs operate by measuring force between a probe and the sample. Normally, the probe is a sharp tip, which is a 3-6 μm tall pyramid with 15-40nm end radius. Though the lateral resolution of AFM is low ($\sim 30\text{nm}$) due to the convolution, the vertical resolution can be up to 0.1nm.



pátek 29. 08. 2014, od 14:00 h

Ústav chemie a biochemie

Kontakt: kizek@sci.muni.cz

